New IEEE 1149.7™ Test and Debug Standard Expands and Improves JTAG Functionality

PISCATAWAY, N.J., -– IEEE, the world's leading professional association for the advancement of technology, announced last week the ratification of IEEE 1149.7™ test and debug standard.

The new standard expands and improves upon IEEE 1149.1 (JTAG) functionality and is designed to maximize space and cost-savings while maintaining previously made industry investments.

Developed in an IEEE working group (WG) led by Texas Instruments Incorporated (TI), IEEE 1149.7 enables manufacturers to accomplish more while using fewer resources. The new standard opens the door to greater innovation by deploying an adaptable but robust framework, facilitating customization for testing and debugging of a wide array of technologies, including highly pin/package-constrained devices such as consumer electronics and mobile communications.

By maintaining backwards-compatibility and leveraging proven tools and infrastructures, IEEE 1149.7 also upholds substantial industry investment in earlier IEEE 1149.x standards.

“IEEE 1149.7 offers a flexible, dynamic solution for designers and engineers contending with shifting design paradigms without eroding the firm foundation established by earlier standards, such as IEEE 1149.1,” said Stephen Lau, emulation technology product manager, Texas Instruments. “The combination of an extraordinary level of customizability with already-proven technologies maximizes IEEE 1149.7’s effectiveness, ensuring its role as an essential, cost-effective test and debug tool.”

The new IEEE 1149.7 standard offers a host of new features and upgrades aimed at addressing unique challenges, such as complex digital circuitry, form factor size constraints, and multiple CPUs, posed by today’s smaller, next-generation consumer electronics. The six classes (T0 – T5) contained within the standard include IEEE 1149.1 extensions, assuring compliance for chips with multiple TAPs.

IEEE 1149.7 was ratified by IEEE’s Standards Board on December 9, 2009 and will be published on February 10, 2010. For additional information on IEEE 1149.7 or the IEEE 1149.7 WG, please visit http://grouper.ieee.org/groups/1149/7/ [1].

Source URL (retrieved on *12/11/2013 - 1:20pm*):
http://www.wirelessdesignmag.com/product-releases/2010/02/new-ieee-11497%E2

%84%A2-test-and-debug-standard-expands-and-improves-jtag-functionality?qt-blogs=0

Links:
[1] http://grouper.ieee.org/groups/1149/7/